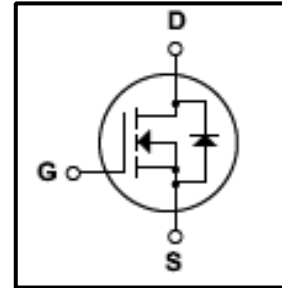


Silicon N-Channel MOSFET

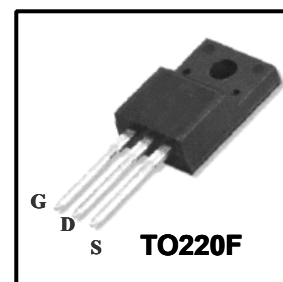
Features

- 18A,200V. $R_{DS(on)}$ (Max 0.18 Ω)@ $V_{GS}=10V$
- Ultra-low Gate Charge(Typical 16nC)
- Fast Switching Capability
- 100%Avalanche Tested
- Isolation Voltage ($V_{ISO} = 4000V$ AC)
- Maximum Junction Temperature Range(150℃)



General Description

This Power MOSFET is produced using Winsemi's advanced Planar stripe, DMOS technology. This latest technology has been especially designed to minimize on-state resistance, have a high rugged avalanche characteristics. This devices is specially well suited for low voltage applications such as automotive, high efficiency switching for DC/DC converters, and DC motor control.



Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{DSS}	Drain Source Voltage	200	V
I_D	Continuous Drain Current(@ $T_c=25^\circ C$)	18*	A
	Continuous Drain Current(@ $T_c=100^\circ C$)	12*	A
I_{DM}	Drain Current Pulsed (Note1)	72*	A
V_{GS}	Gate to Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	258	mJ
E_{AR}	Repetitive Avalanche Energy (Note 1)	13	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	5.5	V/ns
P_D	Total Power Dissipation(@ $T_c=25^\circ C$)	44	W
	Derating Factor above 25℃	0.35	W/℃
T_J, T_{stg}	Junction and Storage Temperature	-55~150	℃
T_L	Channel Temperature	300	℃

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R_{QJC}	Thermal Resistance, Junction-to-Case	-	-	2.85	℃/W
R_{QCS}	Thermal Resistance, Case to Sink	-	0.5	-	℃/W
R_{QJA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	℃/W

Electrical Characteristics (Tc = 25°C)

Characteristics		Symbol	Test Condition	Min	Type	Max	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	± 100	nA
Gate-source breakdown voltage		$V_{(BR)GSS}$	$I_G = \pm 10 \mu\text{A}, V_{DS} = 0 \text{ V}$	± 30	-	-	V
Drain cut-off current		I_{DSS}	$V_{DS} = 200 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	10	μA
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{ V}$	200	-	-	V
Gate threshold voltage		$V_{GS(th)}$	$V_{DS} = 10 \text{ V}, I_D = 250 \mu\text{A}$	2	-	4	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}, I_D = 9 \text{ A}$	-	-	0.18	Ω
Forward Transconductance		g_{fs}	$V_{DS} = 50 \text{ V}, I_D = 9 \text{ A}$	6.7	-	-	S
Input capacitance		C_{iss}	$V_{DS} = 25 \text{ V},$ $V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	-	1300	1760	pF
Reverse transfer capacitance		C_{rss}		-	-	245	
Output capacitance		C_{oss}		-	-	65	
Switching time	Rise time	t_r	$V_{DD} = 100 \text{ V},$ $I_D = 18 \text{ A}$ $R_G = 25 \Omega$ (Note4,5)	-	54	-	ns
	Turn-on time	t_{on}		-	104	-	
	Fall time	t_f		-	327	-	
	Turn-off time	t_{off}		-	108	-	
Total gate charge (gate-source plus gate-drain)		Q_g	$V_{DD} = 160 \text{ V},$ $V_{GS} = 10 \text{ V},$ $I_D = 18 \text{ A}$ (Note4,5)	-	-	70	nC
Gate-source charge		Q_{gs}		-	8	13	
Gate-drain ("miller") Charge		Q_{gd}		-	22	39	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I_{DR}	-	-	-	18	A
Pulse drain reverse current	I_{DRP}	-	-	-	72	A
Forward voltage (diode)	V_{DSF}	$I_{DR} = 18 \text{ A}, V_{GS} = 0 \text{ V}$	-	1.4	1.5	V
Reverse recovery time	t_{rr}	$I_{DR} = 18 \text{ A}, V_{GS} = 0 \text{ V},$ $dI_{DR} / dt = 100 \text{ A} / \mu\text{s}$	-	195	-	ns
Reverse recovery charge	Q_{rr}		-	1.48	-	μC

Note 1.Repeativity rating :pulse width limited by junction temperature

2.L=18.5mH, $I_{AS}=18\text{A}, V_{DD}=50\text{V}, R_G=0\Omega$, Starting $T_J=25^\circ\text{C}$

3. $I_{SD} \leq 18\text{A}, di/dt \leq 300\text{A}/\mu\text{s}, V_{DD} < BV_{DSS}$, STARTING $T_J=25^\circ\text{C}$

4.Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

5.Essentially independent of operating temperature.

This transistor is an electrostatic sensitive device

Please handle with caution

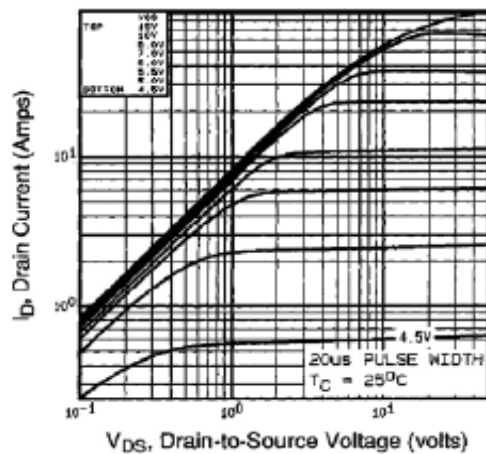


Fig. 1 On-State Characteristics

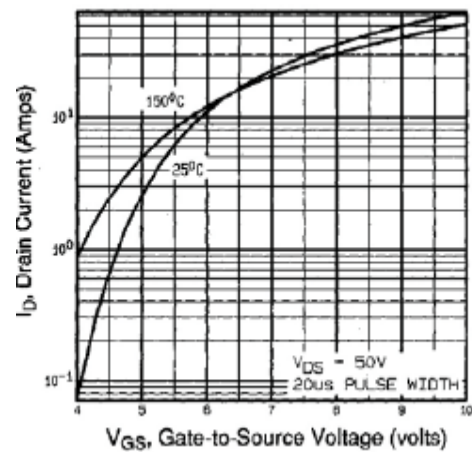


Fig. 2 Transfer Characteristics

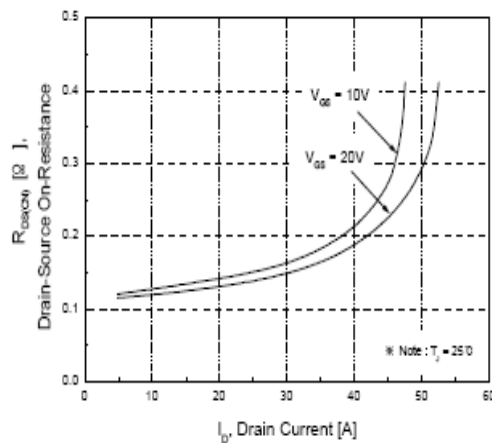


Fig. 3 On-Resistance Variation vs Drain Current

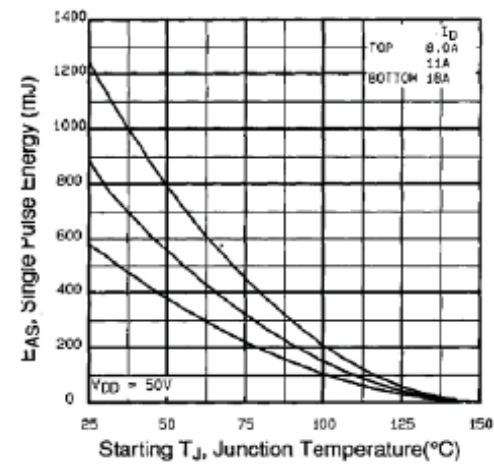


Fig. 4 Maximum Avalanche Energy vs On-State Current

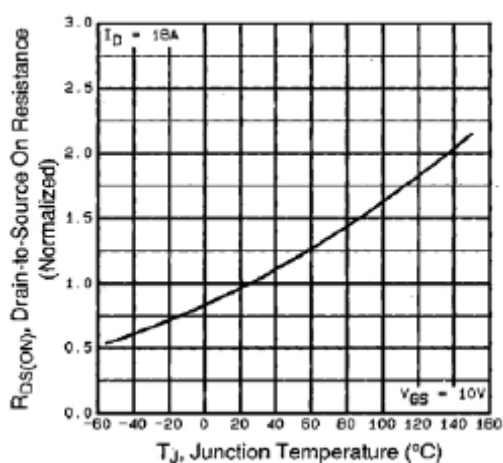


Fig. 5 On-Resistance Variation vs Junction Temperature

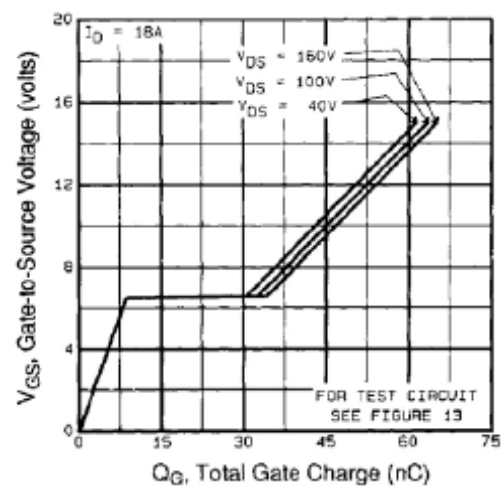


Fig. 6 Gate Charge Characteristics

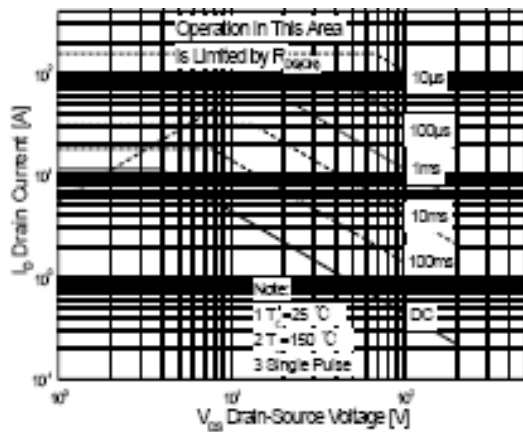


Fig.7 Maximum Safe Operation Area

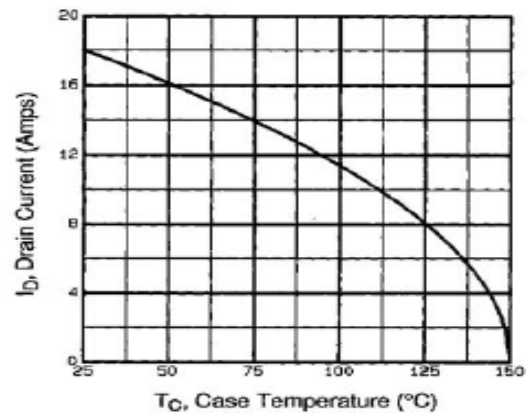


Fig.8 Maximum Drain Current vs Case Temperature

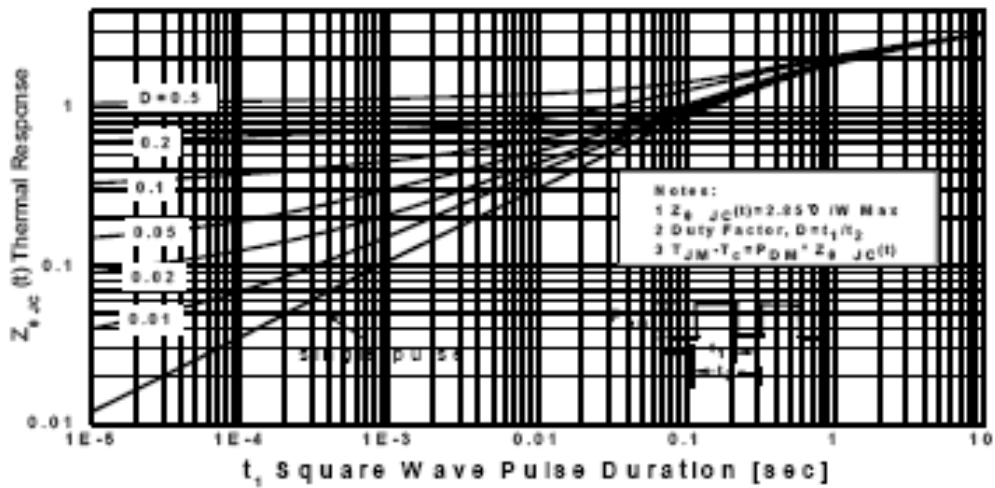


Fig.9 Transient Thermal Response Curve

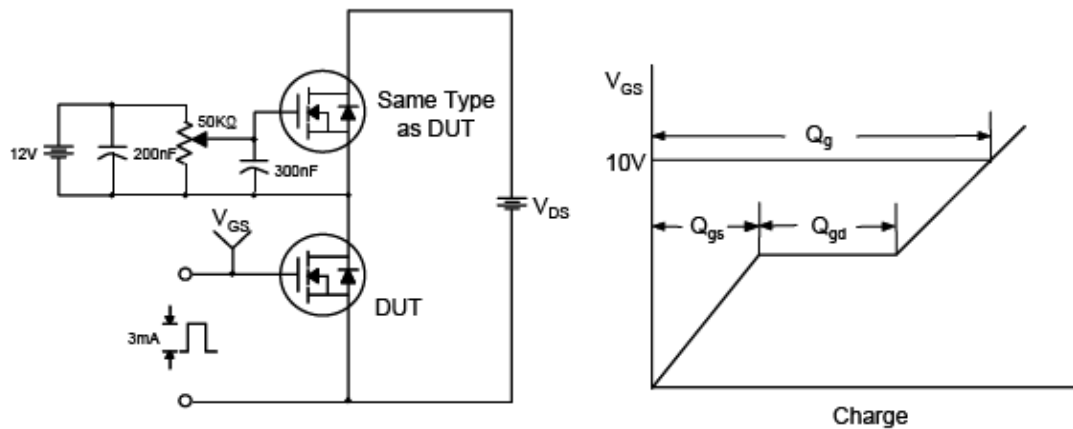


Fig.10 Gate Test Circuit & Waveform

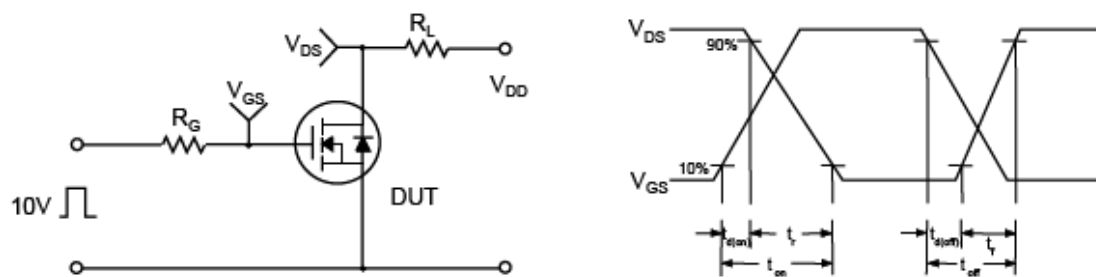


Fig.11 Resistive Switching Test Circuit & Waveform

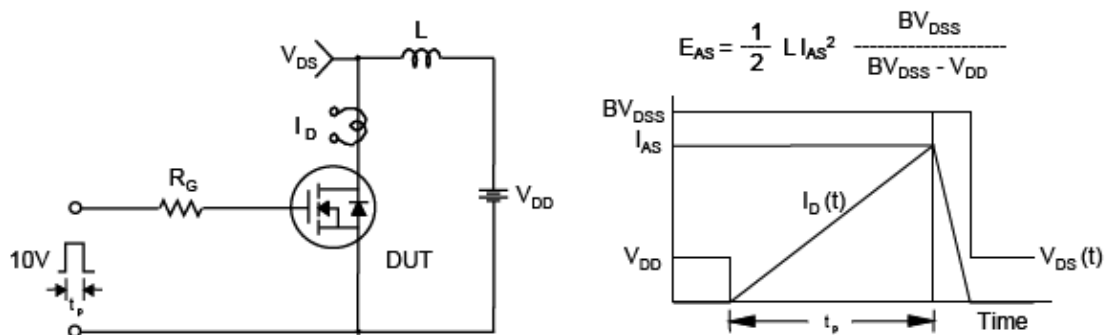


Fig.12 Unclamped Inductive Switching Test Circuit & Waveform

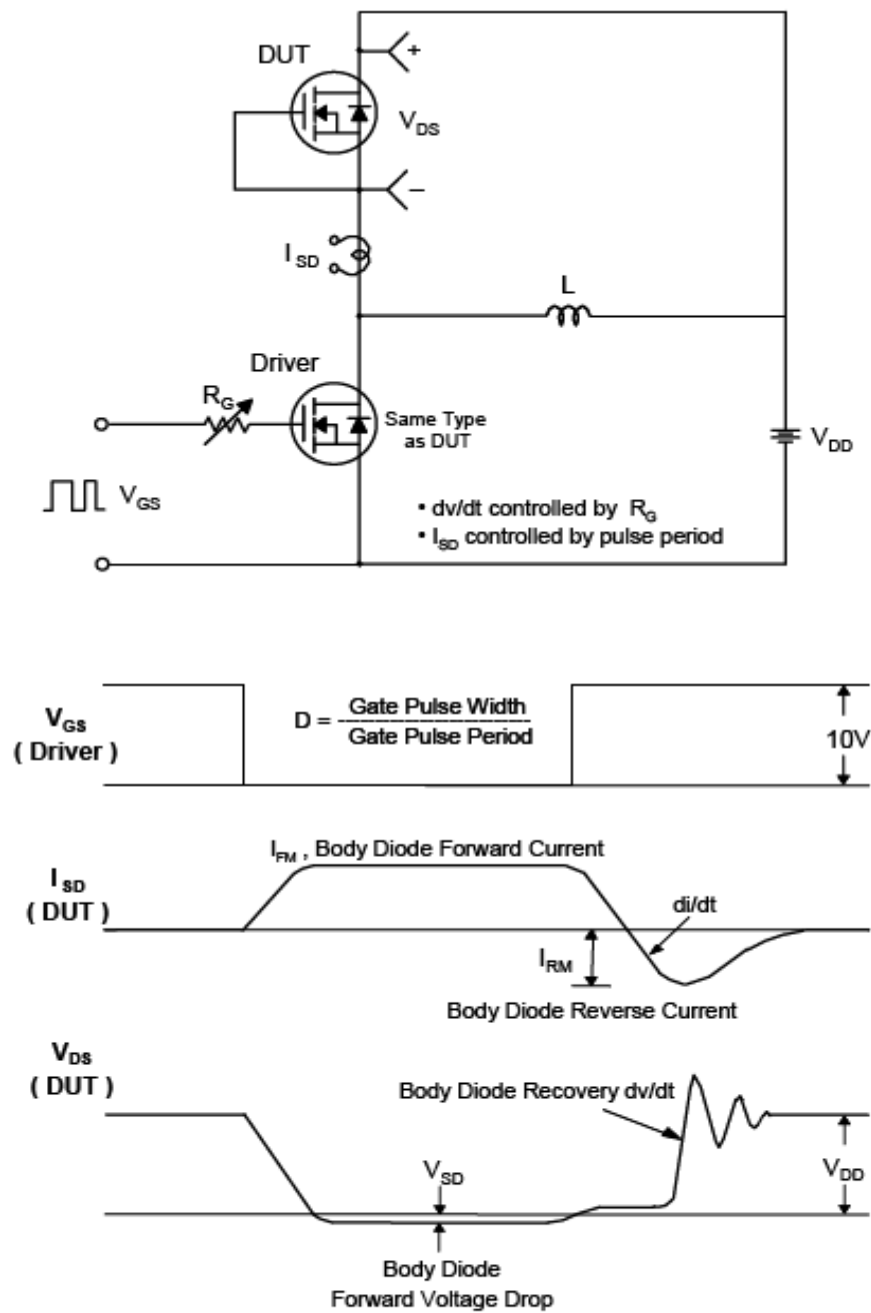


Fig.13 Peak Diode Recovery dv/dt Test Circuit & Waveform

TO-220F Package Dimension

